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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

947
10/03/498
01/03/02

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10034498	01/03/2002	438	151	2812	Smith

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**CONTINUING DATA VERIFIED:

** FOREIGN APPLICATIONS VERIFIED:
JAPAN 2001-010858 01/18/2001 2825

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no		ATTORNEY DOCKET NO
35 USC 119 conditions met <input checked="" type="checkbox"/> yes <input type="checkbox"/> no		740756-2417
Verified and Acknowledged Examiners's initials 2825		
TITLE : Method of manufacturing semiconductor device		

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G.
Assistant Examiner		DRAWING	
ISSUE FEE		Sheets Drwg.	Figs.Drwg.
Amount Due	Date Paid	Print Fig.	
Primary Examiner		Application Examiner	
PREPARED FOR ISSUE			
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